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		JP 2002-536827	10/29/02	Kopp		Abstract
		JP 2005-172876	06/30/05	Kinoshita		Abstract

NON PATENT LITERATURE DOCUMENTS

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		Kopp, V. I., et al., "Twist Defect in Chiral Photonic Structures," *Phys. Rev. Ltrs.*, Vol. 89, No. 3 (July 15, 2002), pp. 033901-1- 033901-4	

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